

Notice of References Cited

Application/Control No.

10/727,301

Applicant(s)/Patent Under
Reexamination
LEAN ET AL.

Examiner

ALEX NOGUEROLA

Art Unit

1753

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,156,970	01-2007	Lean et al.	204/547
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Frénée et al. (« A Multilayer Microelectrode array for Particle separation by Dielectrophoresis, » Micro Total Analysis systems 2002, Volume 1, 578-580, Y. Baba et al. (eds.))
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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